Notice of References Cited

Application/Control No. 10/711,835		Applicant(s)/F Reexamination	Applicant(s)/Patent Under Reexamination SU ET AL.		
Exami	iner	Art Unit			
Thanh	T. Nauven	2813	Page 1 of 1		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2006/0163582	07-2006	Lee et al.	257/066
	В	US-			
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP05-257167	08-1993	Japan	Takahata et al.	G02F 1/136
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
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